## SN54LS386A, SN74LS386A QUADRUPLE 2-INPUT EXCLUSIVE-OR GATES

**SDLS171** 

MARCH 1974 - REVISED MARCH 1988

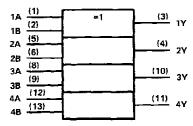
- Electrically Identical to SN54LS86A/SN74LS86A
- Mechanically Identical to SN54L86/SN74L86
- Total Average Propagation Delay Times . . . 10 ns
- Typical Total Power Dissipation . . . 30.5 mW

FUNCTION TABLE (EACH GATE)

INP	UTS	ООТРОТ
A	В	OUTPUT
L	L	L,
L	H	н
Н	L	н
н	Н	L.

H = high level L = law level

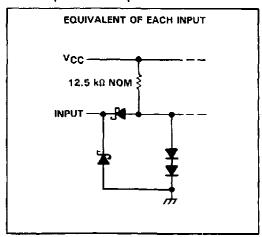
#### logic symbol†

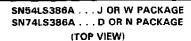


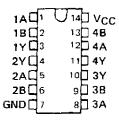
<sup>&</sup>lt;sup>†</sup>This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

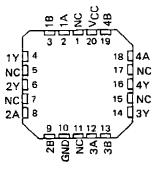
#### schematics of inputs and outputs





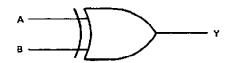


# SN54LS386A . . . FK PACKAGE (TOP VIEW)



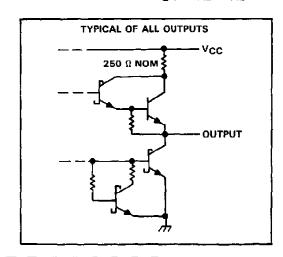
NC ~ No internal connection

#### logic diagram (each gate)



positive logic

$$Y = A \oplus B = \widetilde{AB} + A\overline{B}$$



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## SN54LS386A, SN74LS386A QUADRUPLE 2-INPUT EXCLUSIVE-OR GATES

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)													7 V
Input voltage													7 V
Operating free-air temperature range:	SN54LS386A									-5	5°C	to	125°C
	SN74LS386A												
Storage temperature range									_	-6	5°C	: to	150°C

NOTE 1: Voltage values are with respect to network ground terminal.

#### recommended operating conditions

		SNE	54 LS38	6A	SN	UNIT		
	MI	N	NOM	MAX	MIN	NOM	MAX	ONL
Supply voltage, VCC	4	5	5	5.5	4.75	5	5,25	V
High-level autput current, IOH				-400			-400	μА
Low-level output current, IOL			_	4			8	m,A,
Operating free-air temperature, TA	-5	5		125	0		70	°C

#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	SN	54 LS38	6A_	SV				
PARAMETER	I Ear CO	MIN	TYP	MAX	MIN	TYP‡	MAX	UNIT	
VIH High-level input voltage	7		2			2			V
VIL Low-level input voltage					0.7	]		0.8	V
V <sub>IK</sub> Input clamp voltage	V <sub>CC</sub> = MIN,	I <sub>I</sub> = -18 mA			-1.5			-1.5	V
VOH High-level output voltage	V <sub>CC</sub> = MIN,	V <sub>IH</sub> ≠ 2 V, , I <sub>OH</sub> = –400 μA	2.5	3.4		2.7	3.4		٧
VOI Low-level output voitage	V <sub>CC</sub> = MIN. V <sub>IH</sub> = 2 V,	I <sub>OL</sub> = 4 mA		0.25	0.4		0.25	0.4	v
AUL TOWISMS OF THE CONTRACT	VIL = VIL max	1 <sub>0</sub> L = 8 mA					0.35	0.5	*
I Input current at maximum input voltage	V <sub>CC</sub> = MAX,	V <sub>I</sub> = 7 V	_		0.2			0.2	mΑ
I <sub>IH</sub> High-level input current	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 2.7 V		•	40			40	μΑ
IIL Low-level input current	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 0.4 V			-0.8			8.0-	mA
los Shart-circuit autput current \$	V <sub>CC</sub> = MAX		<b>– 20</b>		_ 100	- 20	·	~ 100	mA
ICC Supply current	V <sub>CC</sub> = MAX,	See Note 2		6.1	10		6.1	10	mA

<sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

### switching characteristics, $VCC \approx 5 \text{ V}$ , $TA = 25^{\circ}C$

PARAMETER	FROM (INPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
tPLH	A or B	Other input low CL = 15		12	23	7.5
tPHL	1	R <sub>L</sub> = 2 k		10	17	ns
tPLH	A or B	Other input high See Note		20	30	ns
tPHL	7 6. 2	Other input mgm 322 itote	`	13	22	1 '''

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

 $<sup>^{\</sup>ddagger}AII$  typical values are at V  $_{CC}$  = 5 V, T  $_{A}$  = 25  $^{\circ}$  C.  $^{\$}$  Not more than one output should be shorted at a time.

NOTE 2:  ${\bf 1}_{CC}$  is measured with the inputs grounded and the outputs open.

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